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SEMICONDUCTOR

November 2013

FQD7N30 N-Channel QFET® MOSFET

300 V, 5.5 A, 700 m Ω

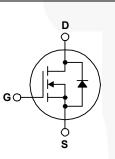
Description

This N-Channel enhancement mode power MOSFET is • 5.5 A, 300 V, $R_{DS(on)}$ = 700 m Ω (Max.) @ V_{GS} = 10 V, produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state D = 2.75 A Low Gate Charge (Typ. 13 nC) resistance, and to provide superior switching performance . Low Crss (Typ. 12 pF) and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power • 100% Avalanche Tested factor correction (PFC), and electronic lamp ballasts.

Features

- I_D = 2.75 A





Absolute Maximum Ratings T_c = 25°C unless otherwise noted.

Symbol	Parameter		FQD7N30TM	Unit
V _{DSS}	Drain-Source Voltage		300	V
ID	Drain Current - Continuous (T _C = 25°C)		5.5	А
	- Continuous (T _C = 100°C)		3.48	А
I _{DM}	Drain Current - Pulsed	(Note 1)	22	A
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		380	mJ
I _{AR}	Avalanche Current	(Note 1)	5.5	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
PD	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds.		300	°C

Thermal Characteristics

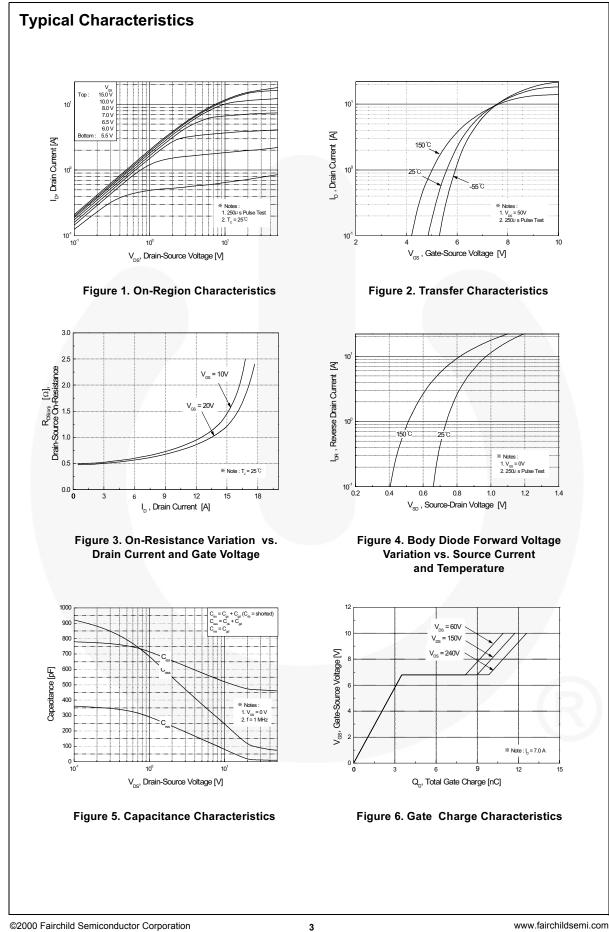
Symbol	Parameter	FQD7N30TM	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	2.5		
Б	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W	
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	50		

FQD7N30 — N-Channel QFET[®] MOSFET

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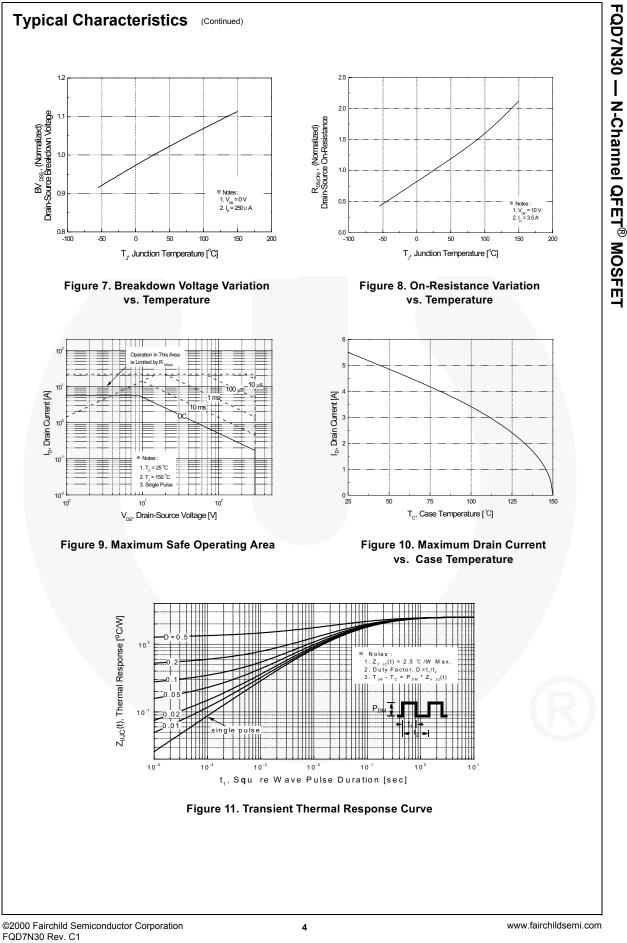
Symbol Off Character BV _{DSS} Drair ΔBV _{DSS} Brea /ΔT Coef ^I DSS Zero ^I GSSF Gate ^I GSSR Gate ^I GSSR Gate ^V GS(th) Gate ^R DS(on) Static On-F On-F ^g FS Forw Dynamic Ch Ciss Coss Outp	Characteristics Parameter Pristics -Source Breakdown Vol down Voltage Tempera icient Gate Voltage Drain Cur Body Leakage Current, Body Leakage Current,	Itage ature rrent , Forward , Reverse	$V_{GS} =$ $I_D = 25$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$ $V_{DS} =$ $V_{DS} =$	herwise noted. Test Conditions $0 \text{ V}, \text{ I}_{\text{D}} = 250 \mu\text{A}$ $50 \mu\text{A}, \text{ Referenced}$ $300 \text{ V}, \text{ V}_{\text{GS}} = 0 \text{ V}$ $240 \text{ V}, \text{ T}_{\text{C}} = 125^{\circ}\text{C}$ $30 \text{ V}, \text{ V}_{\text{DS}} = 0 \text{ V}$ $-30 \text{ V}, \text{ V}_{\text{DS}} = 0 \text{ V}$ $V_{\text{GS}}, \text{ I}_{\text{D}} = 250 \mu\text{A}$ $10 \text{ V}, \text{ I}_{\text{D}} = 2.75 \text{ A}$ $50 \text{ V}, \text{ I}_{\text{D}} = 2.75 \text{ A}$ $25 \text{ V}, \text{ V}_{\text{GS}} = 0 \text{ V},$	to 25°C	Min. 300 3.0 3.0	Typ. 0.3 0.53 4.0	Max 1 10 100 -100 5.0 0.7 	- Unit V'°C μΑ μΑ ηΑ ηΑ ν Ω S
Symbol Off Character BV _{DSS} Drain ΔBV _{DSS} Brea /ΔT Coef ΔBV _{DSS} Zero ΔSSF Gate GSSF Gate VGS(th) Gate RDS(on) Static On-F Forw PFS Forw Dynamic Ch Ciss Ciss Input Crss Rever	Parameter eristics -Source Breakdown Vol cdown Voltage Tempera icient Gate Voltage Drain Cur Body Leakage Current, Body Leakage Current, ristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	Itage ature rrent , Forward , Reverse	$V_{GS} =$ $I_D = 25$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{GS} =$ $V_{DS} =$ $V_{DS} =$	Test Conditions 0 V, I _D = 250 μA 50 μA, Referenced 300 V, V _{GS} = 0 V 240 V, T _C = 125°C 30 V, V _{DS} = 0 V -30 V, V _{DS} = 0 V V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A	to 25°C	300 3.0 	 0.3 0.53	 1 100 -100 5.0 0.7	V V/°C μA nA nA V/°C
Off Characte BV_{DSS} Drain ΔBV_{DSS} Brea $/ \Delta T$ Coef $ DSS$ Zero $ GSSF$ Gate $ GSSR$ Gate $ GSSR$ Gate $QSSR$ Gate $QSSR$ Static On Characte On-Fr $V_{GS(th)}$ Gate $R_{DS(on)}$ Static QFS Forw Dynamic Ch Ciss C_{oss} Outp C_{rss} Rever	eristics -Source Breakdown Vol kdown Voltage Tempera icient Gate Voltage Drain Cur Body Leakage Current, Body Leakage Current, Body Leakage Current, Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	rrent , Forward , Reverse	$I_{D} = 25$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{DS} =$ $V_{DS} =$ $V_{DS} =$	0 V, I _D = 250 μA 50 μA, Referenced 300 V, V _{GS} = 0 V 240 V, T _C = 125°C 30 V, V _{DS} = 0 V -30 V, V _{DS} = 0 V V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A	to 25°C	300 3.0 	 0.3 0.53	 1 100 -100 5.0 0.7	V V/°C μA nA nA V/°C
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	-Source Breakdown Vo kdown Voltage Tempera icient Gate Voltage Drain Cur Body Leakage Current, Body Leakage Current, Pristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	rrent , Forward , Reverse	$I_{D} = 25$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{DS} =$ $V_{DS} =$ $V_{DS} =$	50 μA, Referenced 300 V, V _{GS} = 0 V 240 V, T _C = 125°C 30 V, V _{DS} = 0 V -30 V, V _{DS} = 0 V V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A		 3.0 	0.3 0.53	 1 100 -100 5.0 0.7	V/°C μA ηA nA NA V/°C
ΔBV _{DSS} Brea / ΔT Coef /DSS Zero GSSF Gate GSSR Gate GS(th) Gate RDS(on) Statio On-F On-F GFS Forw Dynamic Ch Ciss Input Coss Outp Crss Rever	kdown Voltage Tempera icient Gate Voltage Drain Cur Body Leakage Current, Body Leakage Current, ristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	rrent , Forward , Reverse	$I_{D} = 25$ $V_{DS} =$ $V_{GS} =$ $V_{GS} =$ $V_{DS} =$ $V_{DS} =$ $V_{DS} =$	50 μA, Referenced 300 V, V _{GS} = 0 V 240 V, T _C = 125°C 30 V, V _{DS} = 0 V -30 V, V _{DS} = 0 V V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A		 3.0 	0.3 0.53	 1 100 -100 5.0 0.7	V/°C μA ηA nA NA V/°C
/ ΔT Coef DSS Zero GSSF Gate GSSR Gate Con Character VGS(th) Gate RDS(on) Static On-F GFS Forw Dynamic Ch Ciss Input Coss Outp Crss Reve	icient Gate Voltage Drain Cur Body Leakage Current, Body Leakage Current, ristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	rrent , Forward , Reverse	$V_{DS} = V_{DS} = V_{GS} = V_{GS} = V_{GS} = V_{DS} = V$	300 V, V _{GS} = 0 V 240 V, T _C = 125°C 30 V, V _{DS} = 0 V -30 V, V _{DS} = 0 V V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A		 3.0 	 0.53	1 100 -100 5.0 0.7	μΑ μΑ nA nA V
Zero I _{GSSF} Gate I _{GSSR} Gate On Characte V _{GS(th)} Gate R _{DS(on)} Station On-F 9FS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Revent	Body Leakage Current, Body Leakage Current, Fristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	, Forward , Reverse	$V_{DS} = V_{GS} = V_{GS} = V_{DS} = V$	240 V, $T_{C} = 125 ^{\circ}C$ 30 V, $V_{DS} = 0$ V -30 V, $V_{DS} = 0$ V V_{GS} , $I_{D} = 250 \mu$ A 10 V, $I_{D} = 2.75$ A 50 V, $I_{D} = 2.75$ A		 3.0 	 0.53	10 100 -100 5.0 0.7	μA nA nA V
I _{GSSR} Gate On Characte V _{GS(th)} Gate R _{DS(on)} Statio On-F 9FS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Reve	Body Leakage Current, ristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance	, Reverse	$V_{GS} =$ $V_{DS} =$ $V_{GS} =$ $V_{DS} =$	-30 V, V _{DS} = 0 V V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A		 3.0 	0.53	-100 5.0 0.7	nA V Ω
I _{GSSR} Gate On Characte V _{GS(th)} Gate R _{DS(on)} Statio On-F 9FS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Reve	ristics Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance		V _{DS} = V _{GS} = V _{DS} =	V _{GS} , I _D = 250 μA 10 V, I _D = 2.75 A 50 V, I _D = 2.75 A		3.0	0.53	5.0 0.7	VΩ
V _{GS(th)} Gate R _{DS(on)} Static ØFS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Rever	Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance		V _{GS} = V _{DS} = V _{DS} =	10 V, I _D = 2.75 A 50 V, I _D = 2.75 A			0.53	0.7	Ω
V _{GS(th)} Gate R _{DS(on)} Static ØFS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Rever	Threshold Voltage Drain-Source esistance ard Transconductance aracteristics Capacitance ut Capacitance		V _{GS} = V _{DS} = V _{DS} =	10 V, I _D = 2.75 A 50 V, I _D = 2.75 A			0.53	0.7	Ω
R _{DS(on)} Static On-F 9FS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Reve	ard Transconductance aracteristics Capacitance ut Capacitance		V _{GS} = V _{DS} = V _{DS} =	10 V, I _D = 2.75 A 50 V, I _D = 2.75 A			0.53	0.7	Ω
gFS Forw Dynamic Ch C _{iss} Input C _{oss} Outp C _{rss} Reve	ard Transconductance aracteristics Capacitance ut Capacitance		V _{DS} =	50 V, I _D = 2.75 A			4.0		S
C _{iss} Input C _{oss} Outp C _{rss} Reve	Capacitance ut Capacitance	_		25 V, V _{GS} = 0 V,					
C _{iss} Input C _{oss} Outp C _{rss} Reve	Capacitance ut Capacitance			25 V, V _{GS} = 0 V,					
C _{oss} Outp C _{rss} Reve	ut Capacitance	_		$25 V, V_{GS} = 0 V,$			470	610	pF
C _{rss} Reve				MHz			100	130	pF
		re l	1 - 1.0				12	16	pF
d(on) Turn	On Delay Time	_	V _{DD} =	150 V, I _D = 7.0 A,			13	35	ns
	On Rise Time	_	R _G = 2	25 Ω			75	160	ns
u(011)	Off Delay Time Off Fall Time		-		(Note 4)		25 35	60 80	ns
	Gate Charge						13	17	ns
	Source Charge		V _{DS} = 1 V _{GS} =	240 V, I _D = 7.0 A,			3.4	17	nC
	Drain Charge		VGS -		(Note 4)		6.4		nC
	-Drain Charge				(0.4		
	e Diode Character num Continuous Drain-			•	5			5.5	•
0	num Pulsed Drain-Sour							5.5 22	A
0	-Source Diode Forward			0 V, I _S = 5.5 A				1.5	V
	rse Recovery Time	, voltage		0 V, I _S = 7.0 A,			150		ns
	rse Recovery Charge			t = 100 A/μs			0.74		μC
L = 21 mH, I_{AS} = 5.5 $I_{SD} \le 7.0$ A, di/dt ≤ 20	se-width limited by maximum ju A, V _{DD} = 50 V, R _G = 25 Ω , start 10 A/µs , V _{DD} ≤ BV _{DSS} , starting ent of operating temperature.	ting T _J = 25°C							

FQD7N30 — N-Channel QFET[®] MOSFET

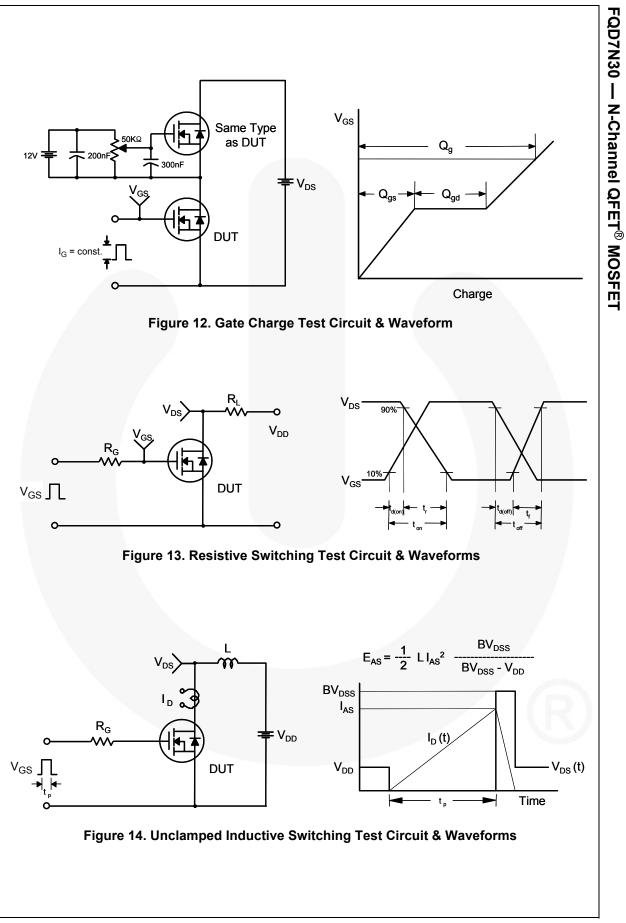


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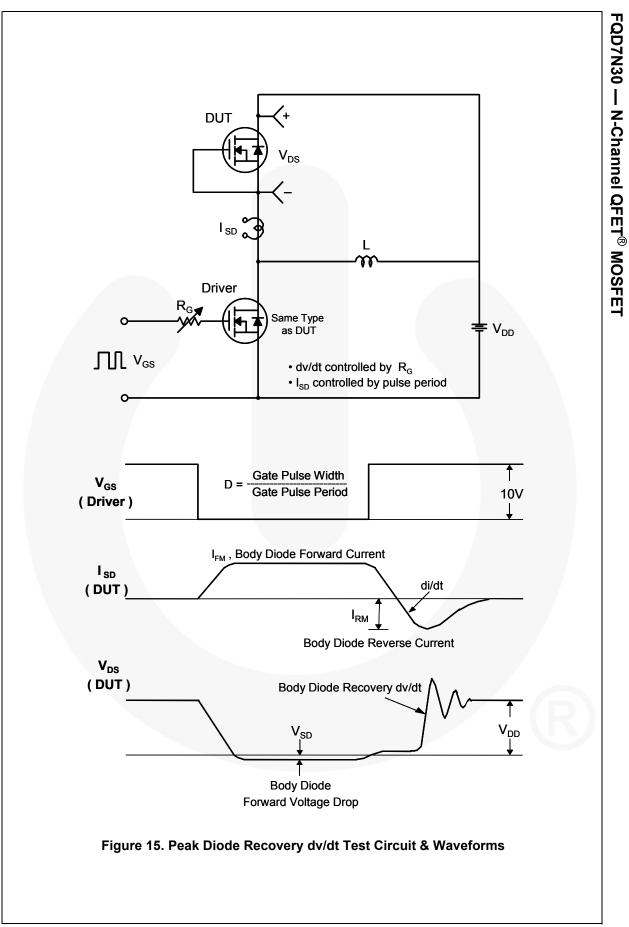
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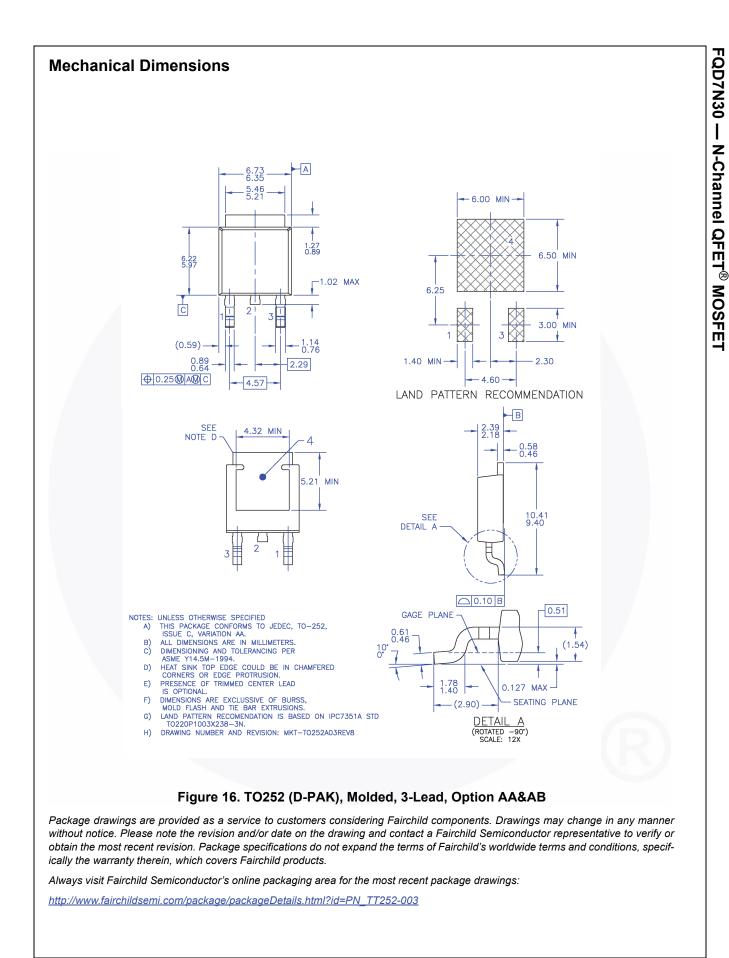


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Rev. 166

QD7N30 ---

N-Channel QFET[®] MOSFET

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